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Kind regards,

Team Nexperia

N-channel TrenchMOS logic level FET Rev. 07 — 30 June 2009

Product data sheet

Product profile 1.

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources

1.3 Applications

DC-to-DC convertors

General purpose switching

1.4 Quick reference data

Table 1.	Quick reference					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	25	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}$	-	-	66	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	93	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	V _{GS} = 5 V; I _D = 50 A; V _{DS} = 15 V; T _j = 25 °C; see <u>Figure 11</u>	-	3.6	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \\ T_{j} = 25 \text{ °C}; \text{ see } \underline{\text{Figure 9}}; \\ \text{see } \underline{\text{Figure 10}} \end{array}$	-	9.1	10.5	mΩ



N-channel TrenchMOS logic level FET

2. Pinning information

Table 2.	Pinning	information					
Pin	Symbol	Description		Simplified outline	Graphic symbol		
1	G	gate			_		
2	D	drain	[1]	mb			
3	S	source					
mb	nb D mounting base; connec drain			1 3 SOT428	mbb076 S		
				(DPAK)			

[1] It is not possible to make a connection to pin 2

3. Ordering information

Table 3.Ordering information

Type number	Package		
	Name	Description	Version
PHD66NQ03LT	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

N-channel TrenchMOS logic level FET

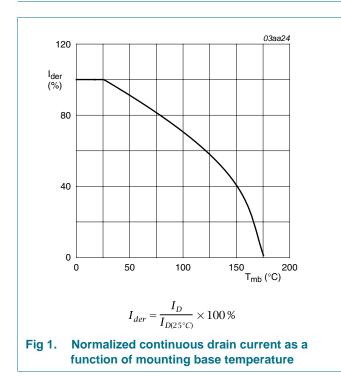
4. Limiting values

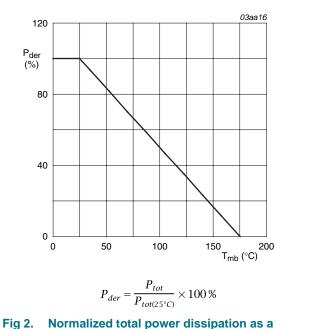
Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	25	V
V _{DGR}	drain-gate voltage	T _j ≥ 25 °C; T _j ≤ 175 °C; R _{GS} = 20 kΩ	-	25	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C	-	45	А
		$V_{GS} = 5 \text{ V}; \text{ T}_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{100 \text{ C}}$	-	40	А
		$V_{GS} = 5 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 3}}; \text{ see } \frac{\text{Figure 3}}{\text{Figure 3}}$	-	57	А
		V _{GS} = 10 V; T _{mb} = 25 °C	-	66	А
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	228	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	93	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-dr	ain diode				
I _S	source current	T _{mb} = 25 °C	-	57	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	228	А
Avalanche	e ruggedness				
E _{DS(AL)S}	non-repetitive	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 43 A; $V_{sup} \le$ 25 V;	-	90	mJ

 $\begin{array}{ll} \mathsf{E}_{\mathsf{DS}(\mathsf{AL})\mathsf{S}} & \text{non-repetitive} & \mathsf{V}_{\mathsf{GS}} = \mathsf{10}\;\mathsf{V}; \;\mathsf{T}_{j(\mathsf{init})} = \mathsf{25}\;^\circ\mathsf{C}; \;\mathsf{I}_\mathsf{D} = \mathsf{43}\;\mathsf{A}; \;\mathsf{V}_{\mathsf{sup}} \leq \mathsf{25}\;\mathsf{V}; \\ \text{drain-source avalanche} & \text{unclamped}; \;\mathsf{t}_\mathsf{p} = \mathsf{0}.\mathsf{15}\;\mathsf{ms}; \;\mathsf{R}_{\mathsf{GS}} = \mathsf{50}\;\Omega \\ \text{energy} \end{array}$



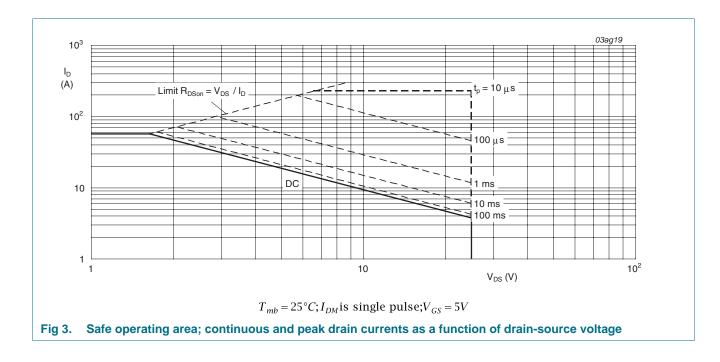




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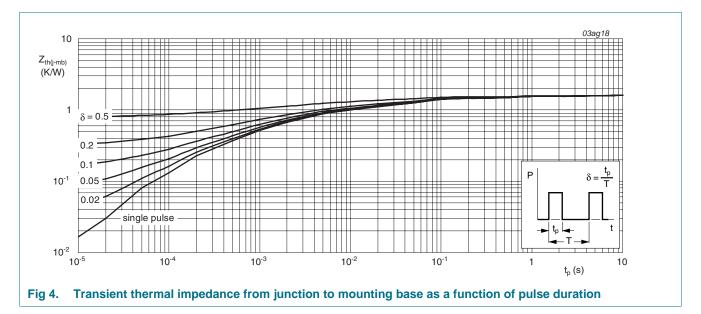
N-channel TrenchMOS logic level FET



N-channel TrenchMOS logic level FET

5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	-	1.6	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in still air	-	75	-	K/W



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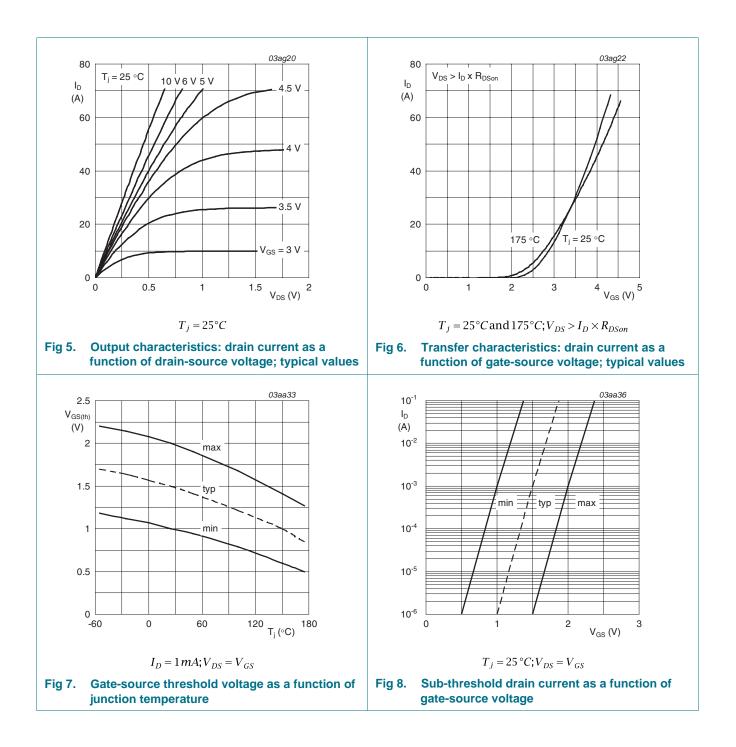
N-channel TrenchMOS logic level FET

6. Characteristics

	Table 6.	Characteristics						
	Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
$ \begin{array}{c} \mbode{breakdown voltage } & b$	Static cha	Static characteristics						
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V _{(BR)DSS}		$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	22	-	-	V	
		breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ\text{C}$	25	-	-	V	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V _{GS(th)}			-	-	2.2	V	
$\begin{tabular}{ c c c c c c } \hline See Figure 7; see Figure 8; \\ \hline See Figure 7; see Figure 8; \\ \hline V_{DS} = 25 V; V_{GS} = 0 V; T_j = 25 °C & - & 10 & \muA \\ \hline V_{DS} = 25 V; V_{OS} = 0 V; T_j = 175 °C & - & 500 & \muA \\ \hline V_{DS} = 25 V; V_{DS} = 0 V; T_j = 25 °C & - & 10 & 100 & nA \\ \hline V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C & - & 10 & 100 & nA \\ \hline V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C & - & 10 & 100 & nA \\ \hline V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C & - & 10 & 100 & nA \\ \hline V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C & - & 10 & 100 & nA \\ \hline V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C & - & 10 & 100 & nA \\ \hline V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C & - & 10 & 100 & nA \\ \hline V_{GS} = 10 V; I_D = 25 A; T_j = 175 °C & - & 11.2 & 13.6 & m\Omega \\ \hline V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C & - & 11.2 & 13.6 & m\Omega \\ \hline See Figure 9; see Figure 10 & - & 9.1 & 10.5 & m\Omega \\ \hline See Figure 9; see Figure 10 & - & 9.1 & 10.5 & m\Omega \\ \hline See Figure 9; see Figure 10 & - & 9.1 & 10.5 & m\Omega \\ \hline See Figure 9; see Figure 10 & - & 9.1 & 10.5 & m\Omega \\ \hline See Figure 9; see Figure 10 & - & 12 & - & nC \\ \hline Q_{GS} gate-source charge & I_D = 50 A; V_{DS} = 15 V; V_{GS} = 5 V; \\ T_j = 25 °C ; see Figure 11 & - & 4.5 & - & nC \\ \hline G_{GS} gate-source charge & T_j = 25 °C ; see Figure 12 & - & 33.6 & - & pF \\ \hline C_{SS} & input capacitance & V_{DS} = 25 V; V_{GS} = 0 V; f = 1 MHz; \\ \hline C_{SS} & reverse transfer \\ \hline capacitance & V_{DS} = 15 V; R_L = 0.6 \Omega; V_{GS} = 5 V; \\ t_i & rise time & V_{DS} = 15 V; R_L = 0.6 \Omega; V_{GS} = 5 V; \\ t_i & rise time & V_{DS} = 15 V; R_L = 0.6 \Omega; V_{GS} = 5 V; \\ f_i & fiall time & - & 25 & 40 & ns \\ t_i & fiall time & - & 25 & 40 & ns \\ \hline Source-drain diode & V_{SD} & source-drain voltage & I_S = 25 A; V_{GS} = 0 V; T_j = 25 °C; & - & 0.95 & 1.2 & V \\ \hline See Figure 13 & t_r & - & 52 °C; & - & 0.95 & 1.2 & V \\ \hline V_{SD} & source-drain voltage & I_S = 10 A; dI_S dI = -100 A/\muS; V_{GS} = 0 V; & - & 32 & - & ns \\ \hline V_{SD} & source-drain voltage & I_S = 10 A; dI_S dI = -100 A/\muS; V_{GS} = 0 V; & - & 32 & - & ns \\ \hline \end{array}$				0.5	-	-	V	
$\begin{tabular}{ c c c c c } \hline V_{DS} = 25 \ V; \ V_{GS} = 0 \ V; \ T_j = 175 \ ^{\circ}C & - & - & 500 \ \mu A \\ \hline V_{GS} = 15 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 10 & 100 \ nA \\ \hline V_{GS} = -15 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 10 & 100 \ nA \\ \hline V_{GS} = -15 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 10 & 100 \ nA \\ \hline V_{GS} = -15 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 10 & 100 \ nA \\ \hline V_{GS} = 5 \ V; \ I_D = 25 \ A; \ T_j = 175 \ ^{\circ}C & - & 11.2 \ 13.6 \ m\Omega \\ \hline v_{GS} = 5 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ}C & - & 11.2 \ 13.6 \ m\Omega \\ \hline v_{GS} = 5 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ}C & - & 9.1 \ 10.5 \ m\Omega \\ \hline v_{GS} = 0 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ}C & - & 9.1 \ 10.5 \ m\Omega \\ \hline v_{GS} = 0 \ V; \ I_D = 25 \ A; \ T_j = 25 \ ^{\circ}C & - & 9.1 \ 10.5 \ m\Omega \\ \hline v_{GS} = gate-source \ charge \ T_j = 25 \ ^{\circ}C & - & 9.1 \ 10.5 \ m\Omega \\ \hline Q_{GS} \ gate-source \ charge \ T_j = 25 \ ^{\circ}C & - & 9.1 \ 10.5 \ m\Omega \\ \hline Q_{GS} \ gate-source \ charge \ T_j = 25 \ ^{\circ}C & - & 0.5 \ - & 12 \ - \ nC \\ \hline Q_{GS} \ gate-drain \ charge \ T_j = 25 \ ^{\circ}C & - & 0.5 \ $				1	1.5	2	V	
	I _{DSS}	drain leakage current	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	10	μA	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$			$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA	
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	I _{GSS}	gate leakage current	V_{GS} = 15 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $			V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	R _{DSon}			-	16.4	18.9	mΩ	
see Figure 9; see Figure 10Dynamic characteristics $Q_{G(tot)}$ total gate charge $I_D = 50 \text{ A}; V_{DS} = 15 \text{ V}; V_{GS} = 5 \text{ V};$ $T_j = 25 ^{\circ}\text{C}; see Figure 11$ -12-nC Q_{GD} gate-source charge $T_j = 25 ^{\circ}\text{C}; see Figure 11$ -4.5-nC Q_{GD} gate-drain charge $V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 ^{\circ}\text{C}; see Figure 12$ -860-pF C_{rss} input capacitance $V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 ^{\circ}\text{C}; see Figure 12$ -330-pF C_{rss} reverse transfer capacitanceT-0.6 \Omega; V_{GS} = 5 \text{ V}; $T_j = 25 ^{\circ}\text{ C}; see Figure 12$ -145-pF $t_{d(on)}$ turn-on delay time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}_{GS} = 5 \text{ V};$ t_r -1525ns $t_{d(off)}$ turn-off delay time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}_{GS} = 5 \text{ V};$ $T_j = 25 ^{\circ}\text{ C}$ -1525ns t_f fall time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}_{GS} = 5 \text{ V};$ $T_j = 25 ^{\circ}\text{ C}$ -1525ns t_f fall time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}_{GS} = 5 \text{ V};$ $T_j = 25 ^{\circ}\text{ C}$ -1525ns t_f fall time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}; \text{ T}_j = 25 ^{\circ}\text{ C};$ -0.951.2VSource-drain voltage $I_S = 25 \text{ A}; \text{ V}_{SS} = 0 \text{ V}; \text{ T}_j = 25 ^$, .	-	11.2	13.6	mΩ	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$				-	9.1	10.5	mΩ	
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	Dynamic	characteristics						
Q_{GD} gate-source charge-3.6-nC Q_{GD} gate-drain charge $V_{DS} = 25 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ f} = 1 \text{ MHz};$ T = 25 °C; see Figure 12- 3.6 -nC C_{rss} output capacitance $T_j = 25 \text{ °C}; \text{ see Figure 12}$ - 3.6 -nC C_{rss} reverse transfer capacitance- 145 -pF C_{rss} reverse transfer capacitance- 145 -pF $t_{d(on)}$ turn-on delay time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}_{GS} = 5 \text{ V};$ t_r - 15 25 ns $t_{d(off)}$ turn-off delay time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}_{GS} = 5 \text{ V};$ t_r - 15 25 ns $t_{d(off)}$ turn-off delay time $V_{DS} = 15 \text{ C}; \text{ T}_{j} = 25 °C$ - 90 135 ns t_q fall time- 25 40 nssSource-drain diode V_{SD} source-drain voltage $I_S = 25 \text{ A}; \text{ V}_{GS} = 0 \text{ V}; \text{ T}_{j} = 25 °C;$ see Figure 13- 0.95 1.2 V t_{rr} reverse recovery time $I_S = 10 \text{ A}; dI_S/dt = -100 \text{ A}/\mus; \text{ V}_{GS} = 0 \text{ V};$ - 32 -ns	Q _{G(tot)}	total gate charge		-	12	-	nC	
$\begin{array}{c c c c c c c c c } \hline C_{iss} & input capacitance & V_{DS} = 25 \ V; \ V_{GS} = 0 \ V; \ f = 1 \ MHz; \\ \hline C_{0ss} & output capacitance & T_{j} = 25 \ ^{\circ}C; \ see \ Figure 12 & - & 330 & - & pF \\ \hline C_{rss} & reverse transfer \\ capacitance & & & & & & & & & & & & & & & & & & &$	Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	4.5	-	nC	
$ \begin{array}{c cccc} C_{oss} & output capacitance \\ C_{rss} & reverse transfer \\ capacitance \\ t_{d(on)} & turn-on delay time \\ t_r & rise time \\ t_{d(off)} & turn-off delay time \\ t_r & fall time \\ \end{array} \begin{array}{c ccccc} V_{DS} = 15 \ V; \ R_L = 0.6 \ \Omega; \ V_{GS} = 5 \ V; \\ R_{G(ext)} = 5.6 \ \Omega; \ T_j = 25 \ ^{\circ}C \\ & - & 15 & 25 & ns \\ - & 90 & 135 & ns \\ - & 25 & 40 & ns \\ - & 25 & 40 & ns \\ \hline & - & 25 & 40 & ns \\ \hline & Source-drain diode \\ \end{array} $ $ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Q_{GD}	gate-drain charge		-	3.6	-	nC	
C_{rss} reverse transfer capacitance-145-pF $t_{d(on)}$ turn-on delay time $V_{DS} = 15 \text{ V}; \text{ R}_L = 0.6 \Omega; \text{ V}_{GS} = 5 \text{ V};$ t_r -1525ns $t_{d(off)}$ turn-off delay time $R_{G(ext)} = 5.6 \Omega; \text{ T}_j = 25 \text{ °C}$ -90135ns $t_{d(off)}$ turn-off delay time-2540ns t_r fall time-2540nsSource-drain diode V_{SD} source-drain voltage $I_S = 25 \text{ A}; \text{ V}_{GS} = 0 \text{ V}; \text{ T}_j = 25 \text{ °C};$ see Figure 13-0.951.2V t_r reverse recovery time $I_S = 10 \text{ A}; dI_S/dt = -100 \text{ A}/\mus; \text{ V}_{GS} = 0 \text{ V};$ -32-ns	C _{iss}	input capacitance		-	860	-	pF	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 12$	-	330	-	pF	
t_r rise time $R_{G(ext)} = 5.6 \ \Omega; T_j = 25 \ ^{\circ}C$ -90135ns $t_{d(off)}$ turn-off delay time-2540ns t_f fall time-2540nsSource-drain diode V_{SD} source-drain voltage $I_S = 25 \ A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C;$ -0.951.2V t_{rr} reverse recovery time $I_S = 10 \ A; \ dI_S/dt = -100 \ A/\mu s; \ V_{GS} = 0 \ V;$ -32-ns	C _{rss}			-	145	-	pF	
trisocurreisocurreisocurreisocurreisocurre $t_{d(off)}$ turn-off delay time-2540ns t_{f} fall time-2540nsSource-drain diode V_{SD} source-drain voltage $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}; see Figure 13-0.951.2Vt_{rr}reverse recovery timeI_S = 10 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};32-ns$	t _{d(on)}	turn-on delay time		-	15	25	ns	
t_f fall time-2540nsSource-drain diode V_{SD} source-drain voltage $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see Figure 13-0.951.2V t_{rr} reverse recovery time $I_S = 10 \text{ A}; dI_S/dt = -100 \text{ A}/\mu s; V_{GS} = 0 \text{ V};$ -32-ns	t _r	rise time	$R_{G(ext)} = 5.6 \ \Omega; \ T_j = 25 \ ^{\circ}C$	-	90	135	ns	
t_f fall time-2540nsSource-drain diode V_{SD} source-drain voltage $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see Figure 13-0.951.2V t_{rr} reverse recovery time $I_S = 10 \text{ A}; dI_S/dt = -100 \text{ A/}\mu s; V_{GS} = 0 \text{ V};$ -32-ns	t _{d(off)}	turn-off delay time		-	25	40	ns	
$V_{SD} \qquad source-drain voltage \qquad I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}; \qquad - \qquad 0.95 \qquad 1.2 \text{V}$ $see \frac{\text{Figure 13}}{\text{I}_{rr}} \qquad reverse \text{ recovery time} \qquad I_S = 10 \text{ A}; \text{dI}_S/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{V}_{GS} = 0 \text{ V}; \qquad - \qquad 32 - \text{ns}$ $V_{GS} = 25 \text{ V}; T_r = 25 \text{ °C}$	t _f	fall time		-	25	40	ns	
see Figure 13 t_{rr} reverse recovery time $I_S = 10 \text{ A}$; $dI_S/dt = -100 \text{ A}/\mu s$; $V_{GS} = 0 \text{ V}$; - 32 - ns	Source-d	rain diode						
$V_{-2} = 25 V_{-1} = 25 \circ C$	V_{SD}	source-drain voltage		-	0.95	1.2	V	
Q_r recovered charge $V_{DS} = 25 \text{ V}; T_j = 25 \text{ °C}$ - 20 - nC	t _{rr}	reverse recovery time		-	32	-	ns	
	Qr	recovered charge	V _{DS} = 25 V; T _j = 25 °C	-	20	-	nC	

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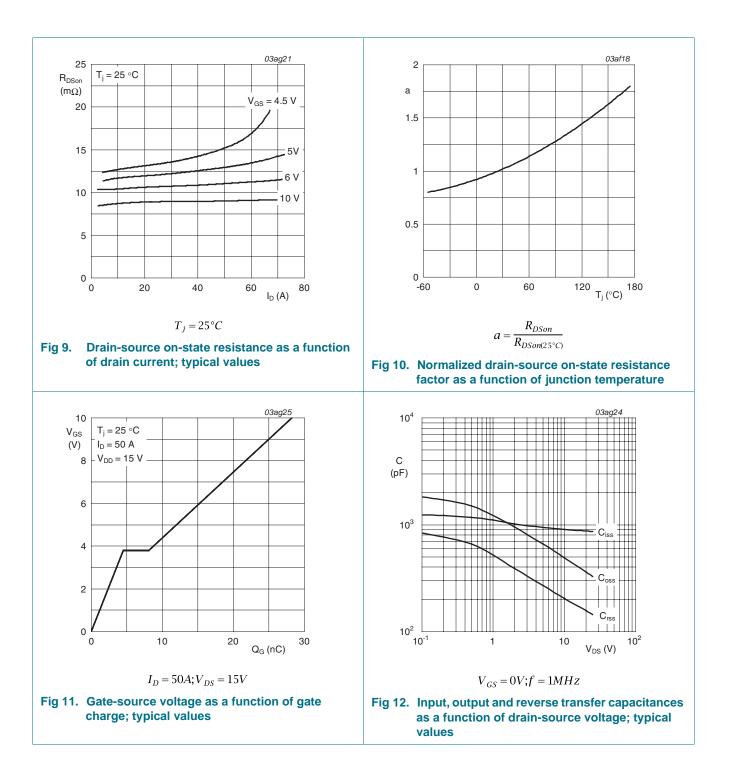
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Product data sheet

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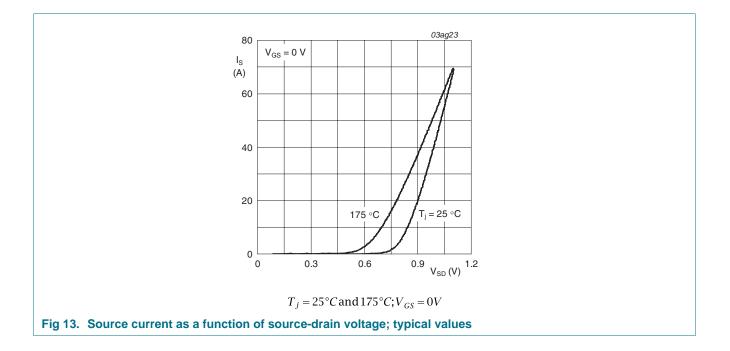


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Product data sheet

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N-channel TrenchMOS logic level FET



N-channel TrenchMOS logic level FET

7. Package outline

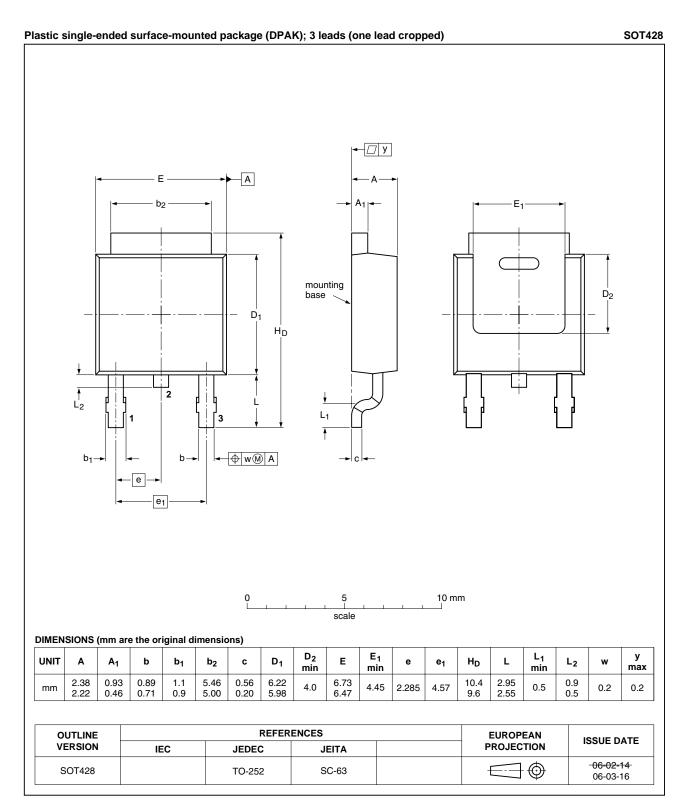


Fig 14. Package outline SOT428 (DPAK)

PHD66NQ03LT_7

Product data sheet

N-channel TrenchMOS logic level FET

8. Revision history

Table 7.Revision history						
Document ID	Release date	Data sheet status	Change notice	Supersedes		
PHD66NQ03LT_7	20090630	Product data sheet	-	PHB_PHD66NQ03LT_6		
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 					
	 Legal texts 	s have been adapted to	the new company r	name where appropriate.		
	 Type num 	ber PHD66NQ03LT sep	arated from data sh	eet PHB_PHD66NQ03LT_6.		
PHB_PHD66NQ03LT_6 (9397 750 13429)	20040802	Product data sheet	-	PHP_PHB_PHD66NQ03LT_5		
PHP_PHB_PHD66NQ03LT_5 (9397 750 13107)	20040415	Product data sheet	-	PHP_PHB_PHD66NQ03LT_4		
PHP_PHB_PHD66NQ03LT_4 (9397 750 10158)	20020909	Product data sheet	-	PHP_PHB_PHD66NQ03LT_3		
PHP_PHB_PHD66NQ03LT_3 (9397 750 09284)	20020312	Product data sheet	-	PHP_PHB_PHD66NQ03LT_2		
PHP_PHB_PHD66NQ03LT_2 (9397 750 09119)	20011210	Product data sheet	-	PHP_PHB_PHD66NQ03LT_1		
PHP_PHB_PHD66NQ03LT_1 (9397 750 08725)	20011012	Product data sheet	-	-		

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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10. Contact information

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